



## OIML Certification System (OIML-CS) Implementation Accreditation in Legal Metrology

### Legal Metrology Experts

Legal Metrology Experts validated by the OIML-CS Management Committee to participate in Accreditation and Peer Assessments under the OIML-CS

Expert Name	Country	OIML Recommendation																			Assessment Experience		
		R 16	R 21	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 117	R 126	R 129	R 134	R 137	R 139	ISO/IEC 17025	ISO/IEC 17065
Petra Milota	AT				✓																	✓	✓
Yi Chen	AU					✓	✓	✓			✓											✓	
Mario Zamora	AU															✓							
Dirk Bils	BE															✓					✓	✓	
Juan Carlos Mateus Sanchez <sup>1</sup>	BR	✓	✓	✓							✓		✓			✓	✓					✓	
Luciano Bruno Faruolo	BR										✓								✓			✓	
Gulian Couvreur	CH						✓	✓	✓		✓			✓	✓				✓			✓	✓
Bernhard Niederhauser	CH																✓					✓	
Wang Jian	CN						✓				✓											✓	
Hu Manhong	CN					✓	✓		✓		✓					✓			✓				
Jiang Jile	CN							✓															
Shi Leibing	CN			✓																			
Yang Jing	CN															✓							
Yang Youtao	CN																			✓			
Zhong Ruilin	CN					✓	✓		✓		✓				✓				✓				
Zhou Shaoyuan	CN			✓																			

1 For EMC tests only

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		R 16	R 21	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 117	R 126	R 129	R 134	R 137	R 139	ISO/IEC 17025	ISO/IEC 17065	
Miroslava Benkova	CZ				✓											✓							✓	
Ivan Kriz	CZ					✓	✓		✓		✓			✓	✓					✓			✓	
Tomás Valenta	CZ																			✓			✓	✓
Timo Schwabe	DE						✓																	
Jürgen Rose	DE									✓													✓	✓
Jens Hovgård Jensen	DK					✓	✓		✓		✓				✓			✓	✓					
Christophe Brun	FR															✓						✓	✓	
Laetitia Delette	FR																✓						✓	
Denis Vogel	FR					✓	✓	✓	✓		✓				✓								✓	
Emeric Morel	FR				✓																		✓	
Luc Lopez <sup>2</sup>	FR		✓				✓			✓	✓	✓				✓								✓
Reuven Perez	IL				✓																		✓	
Ashutosh Agarwal	IN				✓		✓				✓					✓							✓	
Lucio Zotti	IT				✓																		✓	✓
Nobuhiko Azami	JP								✓															
Shinsuke Mikura	JP								✓														✓	
Tomohiro Nagano	JP													✓									✓	
Satoshi Otani	JP													✓									✓	
Takeshi Ito	JP															✓							✓	
Erik Beumer	NL				✓					✓		✓				✓							✓	
Marc Schmidt	NL															✓						✓	✓	
Marcel Cloo	NL			✓																			✓	
Paul van Rooij	NL				✓					✓		✓				✓					✓		✓	
Roy Scholten	NL						✓		✓		✓				✓				✓				✓	
Baris Yilmaz	NL						✓				✓								✓				✓	✓
Hans Boereboom	NL			✓																				
Paul Kok	NL		✓			✓	✓		✓		✓		✓		✓		✓	✓	✓				✓	✓

2 Limited to assessments of OIML Issuing Authorities

Expert Name	Country	OIML Recommendation																				Assessment Experience			
		R 16	R 21	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 117	R 126	R 129	R 134	R 137	R 139	ISO/IEC 17025	ISO/IEC 17065		
Carl Van Wijngaarden	NL																				✓		✓		
Aldemar Tjoa	NL			✓	✓		✓			✓	✓	✓						✓		✓		✓		✓	
Mathias Meijer	NL		✓					✓			✓												✓	✓	✓
Yvo Vermeul	NL										✓											✓			
Srinivas Bobbala	NZ										✓											✓		✓	
Hakan Källgren	SE					✓	✓	✓	✓		✓			✓	✓									✓	✓
Matej Grum	SI					✓	✓		✓		✓			✓	✓									✓	✓
Aleksander Premuš	SI		✓	✓																				✓	✓
Bülent Aydemir	TR					✓	✓	✓	✓		✓			✓	✓						✓			✓	
Sevda Kaçmaz	TR					✓	✓	✓	✓		✓			✓	✓						✓			✓	
Marek Bokota	UK				✓																			✓	✓
Wei Ji	UK							✓																✓	✓
Gregory Glas	UK		✓				✓				✓													✓	✓
Jaco Hattingh	ZA				✓						✓													✓	